

PTO-1449 Information Disclosure Citation in an Application				Application No. 10/661,873		Applicant(s) Edgar Voelkl	
				Docket Number 068062.0167		Group Art Unit 2624	
						Filing Date September 12, 2003	
U.S. PATENT DOCUMENTS							
		DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
J/P/	L.	2307547	08/25/97	GB	G01N	21/88	X
	M.						
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	P.						
NON-PATENT DOCUMENTS							
		DOCUMENT (Including Author, Title, Source, and Pertinent Pages)					DATE
J/P/	Q.	Australian Patent Office Examination Report for Application No. SG 200501488-1 (4 pages)					06/27/06
	R.						
	S.						
	T.						
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EXAMINER					DATE CONSIDERED		
/Jayesh Patel/					05/04/2007		
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.							

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		DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
/JP/	A.	5404221	4/4/95	de Groot	356	349	2/24/93
/JP/	B.	5526116	6/11/96	de Groot	356	354	11/7/94
/JP/	C.	5671050	9/23/97	de Groot	356	359	12/28/94
/JP/	D.	5995224	11/30/99	de Groot	356	355	1/28/98
/JP/	E.	6249351	6/19/01	de Groot	356	512	6/3/99
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08-02-06

IFW

ATTORNEY DOCKET
068062.0167

PATENT APPLICATION
10/661,873



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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: Edgar Voelkl
Serial No.: 10/661,873
Date Filed: September 12, 2003
Group Art Unit: 2625
Examiner: Couso, Yon Jung
Title: **SYSTEM AND METHOD FOR DETECTING
DIFFERENCES BETWEEN COMPLEX IMAGES**

MAIL STOP - AMENDMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

I hereby certify that this Information Disclosure Statement is being deposited with the United States Postal Service as Express Mail No. EV352403825US addressed to: Mail Stop Amendment, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.


Michael Wasaff

8/1/06
Date

Dear Sir:

INFORMATION DISCLOSURE STATEMENT

Applicant respectfully requests, pursuant to 37 C.F.R. §§1.56, 1.97 and 1.98, that the references listed on the attached PTO-1449 form be considered and cited in the examination of the above-identified application. Copies of the references are enclosed for the Examiner's convenience. Furthermore, pursuant to 37 C.F.R. §§1.97(g) and (h), no representation is made that these references are material to the patentability of the present application.

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PATENT APPLICATION
10/661,873

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Applicant believes no fees are due, however, the Commissioner is hereby authorized to charge any fees to Deposit Account No. 50-2148 of Baker Botts L.L.P. in order to effectuate this filing.

Respectfully submitted,

BAKER BOTTS L.L.P.
Attorneys for Applicant



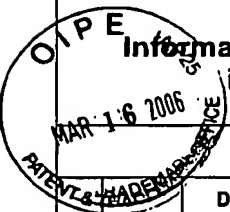
Paula D. Heyman
Reg. No. 48,363

Date: July 27, 2006

Correspondence Address:

Customer No. **31625**

512.322.2581
512.322.8328 (Fax)

PTO-1449 	Application No.		Applicant(s)	
	10/661,873		Edgar Voelkl	
	Docket Number		Group Art Unit	Filing Date
068062.0167		2625	September 12, 2003	

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NON-PATENT DOCUMENTS

	DOCUMENT (Including Author, Title, Source, and Pertinent Pages)	DATE
/JP/s.	Australian Written Opinion; SG 200501488-1; Pgs.5	Mailing Date 1/18/06
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EXAMINER	/Jayesh Patel/	DATE CONSIDERED 05/04/2007
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PTO-1449 <div style="border: 1px solid black; border-radius: 50%; padding: 10px; width: 100px; float: left; margin-right: 10px;"> Information Disclosure Citation in an Application FEB 02 2005 PATENT & TRADEMARK OFFICE </div>		Patent No. 10/661,873 Docket Number 068062.0167		Applicant(s) Edgar Voelkl Group Art Unit 2625 Filing Date September 12, 2003			
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NON-PATENT DOCUMENTS							
		DOCUMENT (Including Author, Title, Source, and Pertinent Pages)					DATE
/JP/	O.	International Search Report for PCT/US03/28877, 8 pages					Mailed 12/28/04
/JP/	P.	Lindlein, et al., <i>Axicon-Type Test Interferometer for Cylindrical Surfaces: Systematic Error Assessment</i> , Applied Optics, Vol. 36, No. 13, pp. 2791-2795					5/1/97
/JP/	Q.	Q. Fu, et al., <i>Correction of Aberrations of an Electron Microscope by Means of Electron Holography</i> , The American Physical Society, Vol. 67, No. 17, pp. 2319-2322					10/21/91
	R.						
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EXAMINER				DATE CONSIDERED			
/Jayesh Patel/				05/04/2007			
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PTO-1449

Patent No.

Applicant(s)

**Information Disclosure Citation
in an Application**

10/661,873

Edgar Voelkl

Docket Number

Group Art Unit

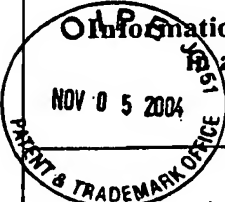
Filing Date

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/JP/	L.	196 46 702 A1	5/28/97	DE	G06K	9/62		X
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NON-PATENT DOCUMENTS

		DOCUMENT (Including Author, Title, Source, and Pertinent Pages)	DATE
/JP/	O.	PCT Invitation to Pay Additional Fees for International Application No. PCT/US03/28877, 6 pages	Mailing Date 10/13/04
/JP/	P.	C.E. Thomas Jr. et al., "Direct to digital holography for semiconductor wafer defect detection and review" Design, Process Integration, and Characterization for Microelectronics, vol. 4692, XP-002282790, pages 180-194	03/2002
/JP/	Q.	E. Volkl et al., "Practical Electron Holography: Applications of Advanced Hologram Processing Techniques to Materials Science Problems" Electron Holography, XP008031237, pages 103-116	08/31/94
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	S.		

EXAMINER /Jayesh Patel/

DATE CONSIDERED

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		Not yet assigned		Edgar Voelkl			
		Docket Number	Group Art Unit	Filing Date			
		068062.0167	Not Yet Assigned	September 12, 2003			
U.S. PATENT DOCUMENTS							
		DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
/JP/A		6,525,821	02/25/03	Thomas et al.	356	457	01/04/00
/JP/B		6,078,392	06/20/00	Thomas et al.	356	348	06/11/97
/JP/C		2003/0048957 A1	03/13/03	Dai et al.	382	260	09/07/01
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/JP/P		U.S. Patent Application Serial No. 09/949,423 entitled <i>System and Method for Registering Complex Images</i> filed by X. Long Dai, et al. on September 7, 2001. 25 Pages.					09/07/01
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